

S-TEST/16 Fab

Production test system for digital sensors



Features

- Can hold 16 UTB cards to connect up to 64 sensors (4 sensors per card)
- Ethernet Interface card (ETH) for system communication, test and firmware loading and self-calibration
- Integrated power supply
- LED system status indicators
- ✓ Parallel sampling with timestamp

©‡ Applications

- System Level Test platform for sensors with digital interfaces
- Sensor final test during sensor mass production
- Sensor characterization and functional validation

Range of use

- Mass-production testing of sensors
- Quality assurance in sensor manufacturing

Specification

The S-TEST /16 Fab is a compact system level test solution (SLT) for sensors with digital interfaces. It can be used to test and characterize digital sensors with up to 16 IO pins. The system is tailored for usage in mass production environments and test floors. It allows easy scaling of testing capacity and can be combined with a wide range of sensor device handling systems. The device can hold up to 16 S-TEST Universal Tester Boards (UTB) that each offers interface resources for up to 4 sensors. The system main communication interface is the Chassis Communication Controller (CCB/ETH15). It offers TCP/IP connectivity, system calibration functionality as well as external trigger inputs and outputs.

③ Technical Data	
Supported number of UTB ¹⁾	16
Max. number of DUT I/O pins	16
Max. number of connectible sensors	Up to 64 ²⁾
Supported digital interfaces	l ² C, mipi I3C, SPI, CAN-FD, LIN, PSI5, SENT, JTAG, TDM, ZACWire
Power supply ranges	100 V240 V, 50/60 Hz
Operating temperature range	20 °C35 °C
Storage temperature range	-25 °C +55 °C
Relative humidity	40 % 80 %
Dimensions (H x W x L)	134 mm x 485 mm x 563 mm (with front handles)
Weight	9.6 kg

All specification are at room temperature unless otherwise specified

1) SPEKTRA S-TEST Universal Tester Board

2) Maximum number of freely assignable IO pins: 16

Accessories (optional)

S-TEST (BSI) Fan unit (1HE)